

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

|                       |                        |           |                             |
|-----------------------|------------------------|-----------|-----------------------------|
| Serial No.            | 10/539,247             | Conf. No. | 9258                        |
| In Re Application of: | Gattiker <i>et al.</i> | Art Unit: | 2829                        |
| Filed:                | 06/16/2005             | Dkt. #:   | BUR920020068US1 (IBMF-0010) |
|                       |                        | Examiner: | Nguyen, Vinh P.             |

Title: **INTEGRATED CIRCUIT TESTING METHODS USING WELL BIAS MODIFICATION**

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT**

Sir:

**I. INTRODUCTORY COMMENTS**

In response to the Office Action of June 11, 2007, please reconsider the above-referenced patent application in light of the following remarks:

**The Claims** are reflected in the listing of claims that begin on page 2 of this paper.

**Remarks** begin on page 9 of this paper.